Application No.: 10/586,909

REMARKS

Claims 1, 5-17 and 19-22 are all the claims pending in the application. Claims 1 and 19

have been amended by this Amendment.

Claim I has been amended for clarity and to address a claim objection and rejections

under 35 U.S.C. § 112, second paragraph, as discussed below. Claim 1 has been further

amended to recite that the at least one gallium nitride compound semiconductor well layer is a

discontinuous layer including a portion having a thickness of 0 nm. Support is found, for

example, at page 13, last paragraph of the specification, which describes that the well layer is not

necessarily a continuous layer, and an area where no well layer is present (i.e., a well layer

portion having a thickness of 0 nm) may be included.

Claim 19 has been amended to conform to amended claim 1.

No new matter has been added. Entry of the Amendment is respectfully requested.

I. Claim Objections

(1) The Examiner objected to claims 1, 5-17 and 19-22 because the recitations of (1) "the

multiple quantum well structure", and (2) "the well layer" of claim 1 lack proper antecedent

basis.

In response, claim 1 has been amended for further clarity and to introduce proper

antecedent basis for "the multiple quantum well structure" and "the well layer".

(2) The Examiner objected to the language "absent a well layer" of claim 1 as being

unclear.

Without acquiescing in the merits of the above rejection, claim 1 has been further

amended to recite that the at least one gallium nitride compound semiconductor well layer is a

discontinuous layer including a portion having a thickness of 0 nm.

Application No.: 10/586,909

Withdrawal of the forgoing claim objections is respectfully requested.

II. Claim Rejection under 35 U.S.C. § 112, Second Paragraph

Claims 1, 5-17 and 19 - 22 were rejected under 35 U.S.C. 112, second paragraph, as being indefinite.

In particular, the Examiner contended that the limitation of "the individual well layers" of the quantum well structure of claim 1 lacks sufficient antecedent basis.

In response, claim 1 has been amended for clarity and to recite that the individual gallium nitride compound semiconductor well layers of the multiple quantum well structure each has the same composition.

It is respectfully submitted that claim 1 as amended fully complies with 35 U.S.C. §112, and withdrawal of the forgoing claim rejection is respectfully requested.

III. Claim Rejections under 35 U.S.C. § 103

Claims 1, 5, 9-11, 16, 17 and 19 were rejected under 35 U.S.C. § 103(a) as allegedly being anticipated by Yamada (US 6,608,330 B1) in view of Sasaoka (US 2003/0042496 A1).

Claims 6-8 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Yamada in view of Sasaoka and Hanaoka et al. (US 5,804,839).

Claims 12, 13 and 15 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Yamada in view of Sasaoka and Morita et al. (US 6,121,636).

Claim 14 was rejected under 35 U.S.C. § 103(a) as being unpatentable over Yamada in view of Sasaoka and in further view of Kaneyama et al. (US 6,452,214 B2).

The above rejections should be withdrawn because Yamada, either alone or in view of Sasaoka, Hanaoka and/or Morita, does not render obvious the presently claimed subject matter for the following reasons.

Application No.: 10/586,909

recitation of "the same composition"

Claim 1 recites that the individual gallium nitride compound semiconductor well layers of the multiple quantum well structure each has the same composition, which limitation is not met by Yamada.

Yamada was cited by the Examiner as disclosing in Figure 1 several layers that form the gallium nitride compound semiconductor well layer 108. The Examiner considered that since all of the (first well) layers are designated with the same number "108" in Figure 1, all of the (first well) layers have the same composition. With regard to the second well layer 109 of Yamada, and in response to Applicants' position that Yamada discloses that well layers 108 and 109 have a different composition, the Examiner asserted that the well layer of Yamada can be interpreted to only comprise well layers 108, and not well layer 109. See pages 18-19 of the Action.

Applicants respectfully disagree.

First, Yamada discloses, at Col. 2 lines 1-7, a light emitting device having a first well layer and a second well layer which clearly differ in In composition.

Further, Yamada describes the following four features regarding interaction between the first and second well layers in Col. 4, lines 16-35:

- [1] In general, it has been understood that where the well layer having flatter composition face with the barrier layer and better crystallinity, then its luminous efficiency is higher.
- [2] However, there may be a certain interactive effect between the first and second well layers adjoining over the barrier layer, in a case of an active layer having multiple quantum well structure including well layers having different luminous peak wavelengths.
- [3] In such case, where the degree of asperity of the second well layer emitting the longer wavelength light is greater than that of the first well layer emitting the shorter wavelength light, the shorter wavelength light from the first well layer is less absorbed in the second well layer.

Application No.: 10/586,909

[4] Further, in such case, the degree of asperity of the second well layer can be optimized to improve the luminous efficiency of the second well

layer.

Particularly, the recitations [2] to [4] of Yamada disclose that, in case of an active layer

having multiple quantum well structure including well layers having different luminous peak

wavelengths, the degree of asperity of the well layer is effective for decreasing the absorption of

light and improving the luminous efficiency. According to Yamada, in case of a multiple

quantum well structure including a plurality of well layers having different luminous peak

wavelengths, the degree of effect of decreasing the absorption of light and improving the

luminous efficiency is determined by the relation of the arrangement of each of the well layers

and the degree of asperity of each of the well layers. Moreover, the above recitations [3] and [4]

of Yamada disclose that the asperity of the second well layer is more important.

The Examiner therefore can not reasonably conclude that the well layer of Yamada can

be interpreted to only comprise well layers 108 where Yamada emphasis both interaction of the

first and second well layer and the importance of the second well layer in achieving Yamada's

objectives.

Thus, for at least the above reasons, the Examiner assertion that the well layer of Yamada

can be interpreted to only comprise well layers 108, and not 109, is incorrect.

recitations of "a discontinuous layer" & "absent well layer"

Further, claim 1, as amended, recites that the at least one gallium nitride compound

semiconductor well layer is a discontinuous layer including a portion having a thickness of 0 nm.

Yamada discloses at Col. 13, lines 20 - 22 that the first and second well layers 108, 109

include dished portions D having thickness less than a half of an average thickness thereof.

Application No.: 10/586,909

However, Yamada clearly does \underline{not} disclose a well layer having a portion with a thickness of 0

nm.

<u>Sasaoka</u>

Sasaoka was relied upon by the Examiner as teaching a gallium nitride compound

semiconductor light-emitting device with barrier layer being doped with a Group IV element at

an average atom density of 1 x 10^{17} cm⁻³ to 5 x 10^{18} cm⁻³ (paragraph [0109]). Sasaoka does not

make up the above-noted deficiencies of Yamada.

There is no motivation for one of ordinary skill in the art to apply the barrier layer to be

Si-doped with a concentration of 10¹⁸ cm⁻³ of Sasaoka, to the multiple quantum well structure of

Yamada.

The object of Sasaoka is to realize a desired highly planer surface morphology without

bringing about non-flatness of the surface of the crystallized nitride-based compound

semiconductor layer caused by the undesired mass-transport (paragraph [0064]).

The only barrier layer disclosed in Sasaoka is a barrier layer having the thickness of 4

nanometers (paragraph [0109]). In view of FIG. 3, Sasaoka discloses only a flat barrier layer.

Further, the invention of Sasaoka is considered to be based on the technical idea that,

where the well layer has flatter composition face with the barrier layer and has better

crystallinity, then its luminous efficiency is higher, in a similar manner to conventional common

techniques.

The invention of Yamada differ considerably from that of Sasaoka with respect to the

composition face between the well layer and the barrier layer. Thus, one of ordinary skill in the

art would not be motivated to apply the invention disclosed in Sasaoka to the multiple quantum

well structure disclosed in Yamada.

Application No.: 10/586,909

Hanaoka and Morita do not make up the above-noted deficiencies of Yamada and

Sasaoka.

Conclusion

In view of the foregoing remarks and the amendments to claim 1, it is respectfully

submitted that Yamada, either alone or in view of Sasaoka, Hanaoka and/or Morita, does not

render obvious the presently claimed gallium nitride compound semiconductor light-emitting

device, as recited in present claim 1.

Applicants respectfully request reconsideration and withdrawal of the foregoing

rejections under 35 U.S.C. § 103.

Reconsideration and allowance of this application are now believed to be in order, and

such actions are hereby solicited. If any points remain in issue which the Examiner feels may be

best resolved through a personal or telephone interview, the Examiner is kindly requested to

contact the undersigned at the telephone number listed below.

The USPTO is directed and authorized to charge all required fees, except for the Issue

Fee and the Publication Fee, to Deposit Account No. 19-4880. Please also credit any

overpayments to said Deposit Account.

Respectfully submitted,

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23373 CUSTOMER NUMBER

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